PROCEEDINGS OF SPIE

Optical Technology and Measurement for Industrial Applications Conference

Takeshi Hatsuzawa Yukitoshi Otani Rainer Tutsch Toru Yoshizawa Editors

17-21 April 2023 Yokohama, Japan

Published by SPIE

Volume 12607

Proceedings of SPIE 0277-786X, V. 12607

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

Optical Technology and Measurement for Industrial Applications Conference, edited by Takeshi Hatsuzawa, Yukitoshi Otani, Rainer Tutsch, Toru Yoshizawa, Proc. of SPIE Vol. 12607, 1260701 · © 2023 SPIE · 0277-786X · doi: 10.1117/12.3011866

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Please use the following format to cite material from these proceedings: Author(s), "Title of Paper," in *Optical Technology and Measurement for Industrial Applications Conference*, edited by Takeshi Hatsuzawa, Yukitoshi Otani, Rainer Tutsch, Toru Yoshizawa, Proc. of SPIE 12607, Seven-digit Article CID Number (DD/MM/YYYY); (DOI URL).

ISSN: 0277-786X

ISSN: 1996-756X (electronic)

ISBN: 9781510663411

ISBN: 9781510663428 (electronic)

Published by

SPI

P.O. Box 10, Bellingham, Washington 98227-0010 USA Telephone +1 360 676 3290 (Pacific Time)

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